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U.S. Department of Commerce, Patent and Trademark Office		Docket No.	Serial No.
		2735/PDC/JB	09/111,454
LIST OF RELEVANT ART CITED BY APPLICANT		Applicant	
(Use several sheets if necessary)		Ben-Porath et al	
		Filing Date	Group
		July 8, 1998	2723

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents

							Translation	
		Document Number	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

VB	AR	"Electron Beam Pattern Inspection System Using Digital Image Processing"; Saitoh et al; J. Vac. Sci Technol B. Vol 4, No. 3 May/June 1986 - Pages 686-691
VB	AS	"Inspection For Defects of A Mask Containing One- to Submicrometer Patterns Using a Scanning Electron Microscope and Feature Extraction Method"; Y. Goto, et al; J. Vac. Sci. Technol 15 (3)0 May/June 1976; Pages 953-956
VB	AT	"Studies on an Electron-Beam Mask-defect Inspection System"; Y. Wada et al; J. Vac Sci Technol Vol 19 No. 1 May/June 1981

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Date Considered

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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Porath, et al

Filing Date

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2723

U.S. Patent Document

*Examiner Initial	Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
VB	AA 5,862,055	1/19/99	Chen et al			RECEIVED
	AB					MAR 16 1999
	AC					Group 2700
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

Foreign Patent Documents

							Translation	
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(PTO-1449)

SERIAL NO.
09/111,454

FILING DATE
July 08, 1998

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U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

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